

EAST: [10662810:silicon gate having two crystal faces.wsp:1]

FileViewEditToolsWindowHelp

Drafts

BRS:

BRS:

BRS:

BRS: knall

BRS: 19.21.23

BRS: 32with 33

Pending

Active

L1: (250718) (s7)icid\$4 silicat\$4)

L2: (87757) (crystal near2 (orient\$4 grow\$4 face\$2 facing state) )

L3: (863838) (polysilicon polycrystalline) silicon

L4: (866667) gate

L5: (5752055) ( different "same")

L6: (3305000) ( different)

L7: (895) 2 near 8

L8: (8) 7 same 4

L11: (2892) 2 near 2 5

L12: (44) 11 same 4

L13: (2) 12 same 1

L14: (14) 11 same 1

L15: (8) 14 and 4

L16: (14) 8 15

Failed

Saved

(1) 09/948877

(1778) "CONVINT IIVE BUILD IDS"

BrowseQueueClear

DBs:USPAT:US PGPUB: EPO: JPO: DERWENT: IBM: TDB

Default operator: OR

Plurals

Highlight all bit terms initially

815

June 2004

	U	T	Inventor	Document#	Issue	P	Title	Current	Current XM	Review	S	C	P	A	3	4	5	6	7	8	9	Image	Doc	P
1			Kohno, Yasuh	US 6180986	20010	1	Trench gate type semiconductor device with	257/173	257/174		F	F	F	F	F	F	F	F	F	F	F	US 618098	F	
2			Iijima, Tadas	US 5803053	18890	4	Semiconductor device	257/751	257/764		F	F	F	F	F	F	F	F	F	F	F	US 580305	F	
3			Hayakawa, Y	US 2004008	20040	2	Semiconductor device and method for manuf	257/412			F	F	F	F	F	F	F	F	F	F	F	US 200400	F	
4			Arao, Tatsuy	US 2004007	20040	3	Semiconductor device and method for manuf	257/66			F	F	F	F	F	F	F	F	F	F	F	US 200400	F	
5			Ellison, Alexa	US 2003007	20030	2	High resistivity silicon carbide single crystal	117/88	117/105		F	F	F	F	F	F	F	F	F	F	F	US 200300	F	
6			Zhang, Hongy	US 2001002	20010	1	Semiconductor device and method of manufa	257/59	257/347		F	F	F	F	F	F	F	F	F	F	F	US 200100	F	
7			Zhang, Hongy	US 6225645	20010	2	Semiconductor device and method of manufa	257/59	257/347		F	F	F	F	F	F	F	F	F	F	F	US 622564	F	
8			Yamazaki, Sh	US 5986288	19991	1	Semiconductor device and a method of manu	257/85	257/347		F	F	F	F	F	F	F	F	F	F	F	US 598628	F	
9			Zhang, Hongy	US 5922125	19990	1	Semiconductor device and method of manufa	117/9	117/10		F	F	F	F	F	F	F	F	F	F	F	US 592212	F	
10			Matsubara, Y	US 5587590	18861	1	Test piece for X-ray inspection	257/48	257/384		F	F	F	F	F	F	F	F	F	F	F	US 558759	F	

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Ready

3/1/04